Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/658,190	ADACHI ET AL.	
Examiner	Art Unit	
Yon Couso	2624	

					
SEARCHED					
Class	Subclass	Date	Examiner		
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348	409	8-15-07	m		
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386	111 122 46 68 79 65				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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